

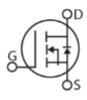
MSC040SMA120S Silicon Carbide N-Channel Power MOSFET

1 Product Overview

The silicon carbide (SiC) power MOSFET product line from Microsemi increases the performance over silicon MOSFET and silicon IGBT solutions while lowering the total cost of ownership for high-voltage applications. The MSC040SMA120S device is a 1200 V, $40~\text{m}\Omega$ SiC MOSFET in a TO-268 (D3PAK) package.



1—Gate 2—Drain 3—Source Backside—Drain



1.1 Features

The following are key features of the MSC040SMA120S device:

- Low capacitances and low gate charge
- Fast switching speed due to low internal gate resistance (ESR)
- Stable operation at high junction temperature, T_{J(max)} = 175 °C
- Fast and reliable body diode
- Superior avalanche ruggedness
- RoHS compliant

1.2 Benefits

The following are benefits of the MSC040SMA120S device:

- High efficiency to enable lighter, more compact system
- Simple to drive and easy to parallel
- Improved thermal capabilities and lower switching losses
- Eliminates the need for external freewheeling diode
- Lower system cost of ownership

1.3 Applications

The MSC040SMA120S device is designed for the following applications:

- PV inverter, converter, and industrial motor drives
- Smart grid transmission and distribution
- Induction heating and welding
- H/EV powertrain and EV charger
- Power supply and distribution



2 Device Specifications

This section shows the specifications for the MSC040SMA120S device.

2.1 Absolute Maximum Ratings

The following table shows the absolute maximum ratings for the MSC040SMA120S device.

Table 1 • Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
VDSS	Drain source voltage	1200	V
lo	Continuous drain current at Tc = 25 °C	64	Α
	Continuous drain current at Tc = 100 °C	45	
I _{DM}	Pulsed drain current ¹	159	
V _G S	Gate-source voltage	23 to -10	٧
PD	Total power dissipation at Tc = 25 °C	303	W
	Linear derating factor	2.02	W/°C

Note:

1. Repetitive rating: pulse width and case temperature limited by maximum junction temperature.

The following table shows the thermal and mechanical characteristics of the MSC040SMA120S device.

Table 2 • Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit
Rөлс	Junction-to-case thermal resistance		0.33	0.50	°C/W
T _J	Operating junction temperature	-55		175	°C
Тѕтб	Storage temperature	- 55		150	_
TL	Soldering temperature for 10 seconds (1.6 mm from case)			260	_
Wt	Package weight		0.14		OZ
			4.0		g



2.2 Electrical Performance

The following table shows the static characteristics for the MSC040SMA120S device. $T_J = 25$ °C unless otherwise specified.

Table 3 • Static Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	V_{GS} = 0 V, I_D = 100 μA	1200			V
R _{DS(on)}	Drain-source on resistance 1	$V_{GS} = 20 \text{ V}, I_D = 40 \text{ A}$		40	50	mΩ
V _{GS(th)}	Gate-source threshold voltage	$V_{GS} = V_{DS}$, $I_D = 2 \text{ mA}$	1.8	2.6		V
$\Delta V_{GS(th)}/\Delta T_J$	Threshold voltage coefficient	$V_{GS} = V_{DS}$, $I_D = 2 \text{ mA}$		-4.5		mV/°C
loss	Zero gate voltage drain current	V _{DS} = 1200 V, V _{GS} = 0 V			100	μΑ
		V _{DS} = 1200 V, T _J = 125 °C, V _{GS} = 0 V			500	-
lgss	Gate-source leakage current	V _{GS} = 20 V/–10 V			±100	nA

Note:

1. Pulse test: pulse width $< 380 \mu s$, duty cycle < 2%.

The following table shows the dynamic characteristics for the MSC040SMA120S device. $T_J = 25$ °C unless otherwise specified.

Table 4 • Dynamic Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
Ciss	Input capacitance	V _{GS} = 0 V, V _{DD} = 1000 V, V _{AC} = 25 mV, f = 1 MHz —		1990		pF
Crss	Reverse transfer			17		-
	capacitance					
Coss	Output capacitance			156		-
Qg	Total gate charge	$V_{GS} = -5 \text{ V/20 V}, V_{DD} = 800 \text{ V}, I_D = 40 \text{ A}$		137		nC
Qgs	Gate-source charge	- -		29		-
Qgd	Gate-drain charge			31		=
td(on)	Turn-on delay time	$V_{DD} = 800 \text{ V}, V_{GS} = -5 \text{ V/20 V}, I_D = 40 \text{ A},$		24		ns
tr	Current rise time	Freewheeling diode = $- MSC040SMA120S (V GS = -5 V)$		13		=
t _{d(off)}	Turn-off delay time			46		_
tf	Current fall time			13		-
Eon	Turn-on switching energy ²			560		μЈ
Eoff	Turn-off switching energy	·		82		_
td(on)	Turn-on delay time	$V_{DD} = 800 \text{ V}, V_{GS} = -5 \text{ V}/20 \text{ V}, I_D = 40 \text{ A},$		23		ns
tr	Current rise time	$R_{G(ext)} = 4 \Omega^{1}$		10		=
t _{d(off)}	Turn-off delay time	Freewheeling diode = MSC015SDA120B		44		-
tf	Current fall time	-		11		-
Eon	Turn-on switching energy ²	-	-	275		μЈ
Eoff	Turn-off switching energy	-		83		=
ESR	Equivalent series resistance	f = 1 MHz, 25 mV, drain short		1.2		Ω



Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
SCWT	Short circuit withstand time	V _{DS} = 960 V, V _{GS} = 20 V, T _C = 25 °C		3		μs
Eas	Avalanche energy, single pulse	$V_{DS} = 150 \text{ V}, V_{GS} = 20 \text{ V}, I_D = 40 \text{ A},$ $T_C = 25 ^{\circ}\text{C}$		2000		mJ

Notes:

- 1. R_G is total gate resistance excluding internal gate driver impedance. 2. E_{on} includes energy of the freewheeling diode.



2.3

Body Diode CharacteristicsThe following table shows the body diode characteristics for the MSC040SMA120S device. T_J = 25 °C unless otherwise specified.

Table 5 • Body Diode Characteristics

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V _{SD}	Diode forward voltage	I _{SD} = 40 A, V _{GS} = 0 V		3.9		V
V _{SD}	Diode forward voltage	$I_{SD} = 40 \text{ A}, V_{GS} = -5 \text{ V}$		4.1		V
trr	Reverse recovery time	$I_{SD} = 40 \text{ A}, V_{GS} = -5 \text{ V}$		31		ns
Qrr	Reverse recovery charge	- V _{DD} = 800 V _ dl/dt = -1800 A/us		610		nC
Irrm	Reverse recovery current	_ αι, ατ 1000 Αγ μ3		40		Α



2.4 Typical Performance Curves

This section shows the typical performance curves for the MSC040SMA120S device.

Figure 1 • Drain Current vs. Drain-to-Source Voltage

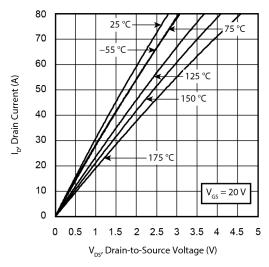


Figure 3 • Drain Current vs. Drain-to-Source Voltage

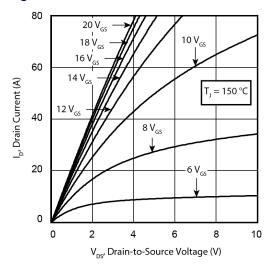


Figure 2 • Drain Current vs. Drain-to-Source Voltage.

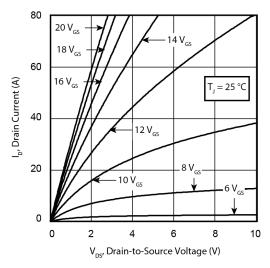


Figure 4 • Drain Current vs. Drain-to-Source Voltage

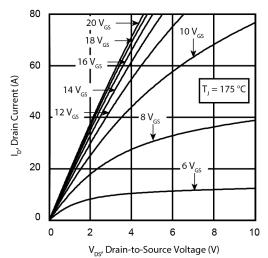




Figure 5 • RDS(on) vs. Junction Temperature

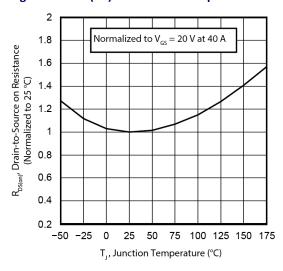


Figure 7 • Capacitance vs. Drain-to-Source Voltage

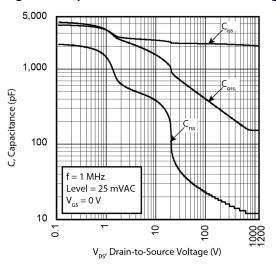


Figure 9 • IDM vs. VDS Third Quadrant Conduction

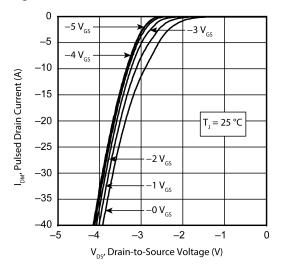


Figure 6 • Gate Charge Characteristics

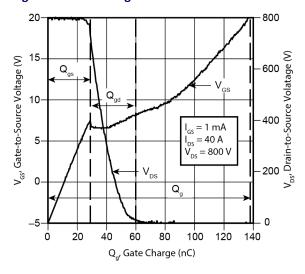


Figure 8 ● IDM vs. Gate-to-Source Voltage

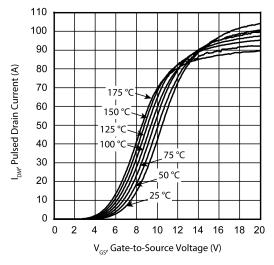


Figure 10 • IDM vs. VDS Third Quadrant Conduction

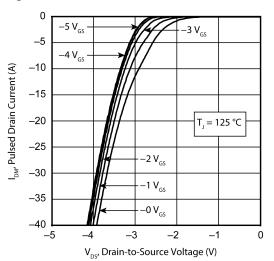




Figure 11 • VGS(th) vs. Junction Temperature

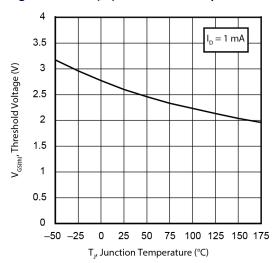


Figure 12 • Forward Safe Operating Area

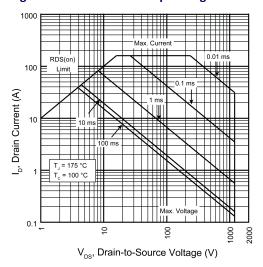
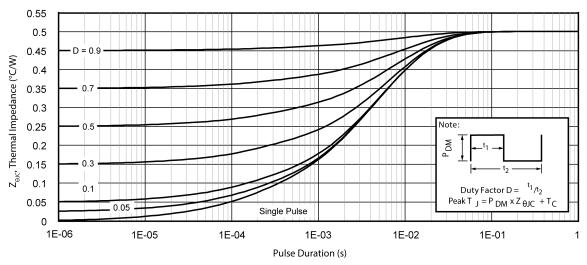


Figure 13 • Maximum Transient Thermal Impedance





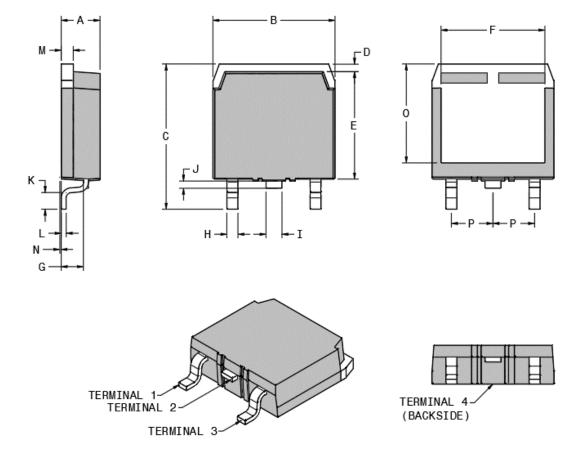
Package Specification 3

This section shows the package specification for the MSC040SMA120S device.

3.1

Package Outline Drawing
The following figure illustrates the TO-268 package outline of the MSC040SMA120S device.

Figure 14 • Package Outline Drawing





The following table lists the TO-268 dimensions and should be used in conjunction with the package outline drawing.

Table 6 • TO-268 Dimensions

Symbol	Min (mm)	Max (mm)	Min (in.)	Max (in.)
Α	4.90	5.10	0.193	0.201
В	15.85	16.20	0.624	0.638
С	18.70	19.10	0.736	0.752
D	1.00	1.25	0.039	0.049
E	13.80	14.00	0.543	0.551
F	13.30	13.60	0.524	0.535
G	2.70	2.90	0.106	0.114
Н	1.15	1.45	0.045	0.057
I	1.95	2.21	0.077	0.087
J	0.94	1.40	0.037	0.055
К	2.40	2.70	0.094	0.106
L	0.40	0.60	0.016	0.024
М	1.45	1.60	0.057	0.063
N	0.00	0.18	0.000	0.007
0	12.40	12.70	0.488	0.500
Р	5.45 BSC (no	m.)	0.215 BSC (nom.)
Terminal 1	Gate			
Terminal 2	Drain			
Terminal 3	Source			
Terminal 4	Drain			





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